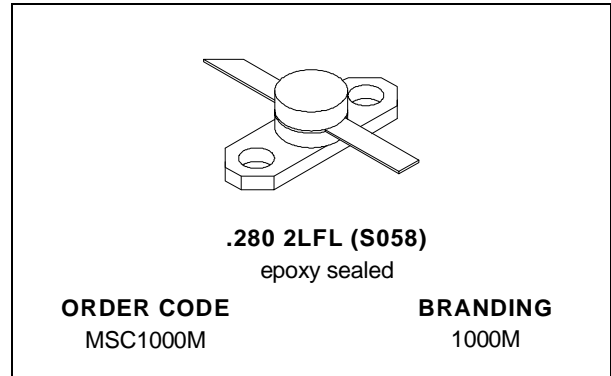


RF & MICROWAVE TRANSISTORS AVIONICS APPLICATIONS

- RUGGEDIZED VSWR $\infty:1$
- INPUT MATCHING
- LOW THERMAL RESISTANCE
- CLASS A OPERATION
- $P_{OUT} = 0.6$ W MIN. WITH 10.8 dB GAIN

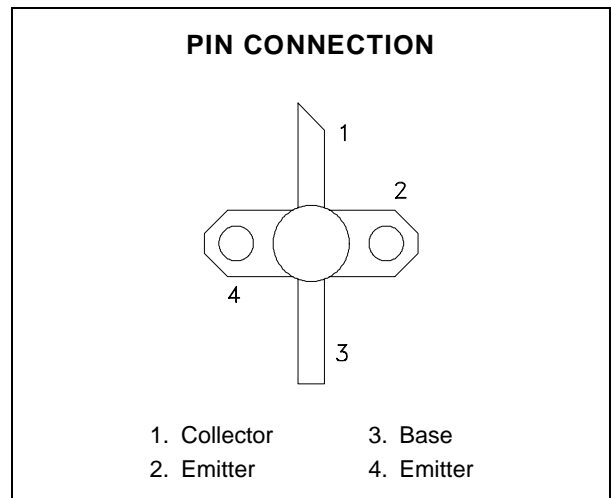


DESCRIPTION

The MSC1000M is a Class A, common emitter transistor with an emitter ballasted Matrix geometry specifically designed for DME/IFF driver applications.

This device is capable of withstanding a $\infty:1$ load VSWR at any phase angle under full rated conditions. Low RF thermal resistance and semi-automatic wire bonding techniques ensure high reliability and product consistency.

The MSC1000M is housed in the IMPAC™ package with internal input matching.



ABSOLUTE MAXIMUM RATINGS ($T_{case} = 25^{\circ}C$)

Symbol	Parameter	Value	Unit
P_{DISS}	Power Dissipation* (See Safe Area)	—	W
I_C	Device Current*	300	mA
V_{CE}	Collector-Emitter Bias Voltage*	20	V
T_J	Junction Temperature (Pulsed RF Operation)	200	$^{\circ}C$
T_{STG}	Storage Temperature	- 65 to +150	$^{\circ}C$

THERMAL DATA

$R_{TH(j-c)}$	Junction-Case Thermal Resistance*	35	$^{\circ}C/W$
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*Applies only to rated RF amplifier operation

MSC1000M

ELECTRICAL SPECIFICATIONS (T_{case} = 25°C)

STATIC

Symbol	Test Conditions		Value			Unit
			Min.	Typ.	Max.	
BV _{CBO}	I _C = 1mA	I _E = 0mA	50	—	—	V
BV _{EBO}	I _E = 1mA	I _C = 0mA	3.5	—	—	V
BV _{CEO}	I _C = 5mA	I _B = 0mA	20	—	—	V
I _{CES}	V _{CE} = 28V		—	—	1.0	mA
h _{FE}	V _{CE} = 5V	I _C = 100mA	15	—	120	—

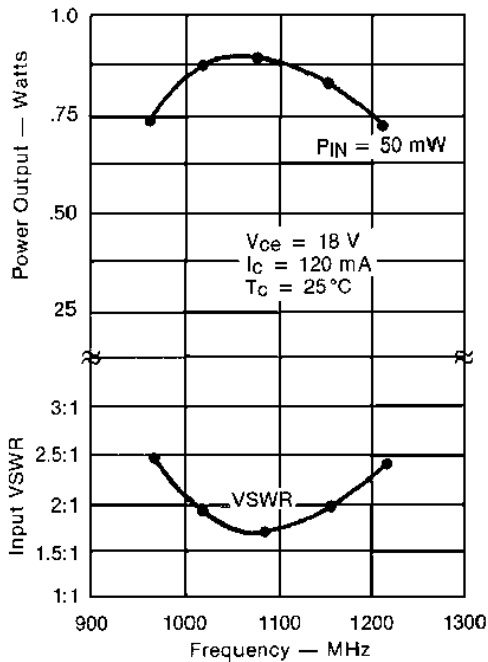
DYNAMIC

Symbol	Test Conditions			Value			Unit
				Min.	Typ.	Max.	
P _{OUT}	f = 1025 — 1150 MHz	P _{IN} = 50 mW	V _{CE} = 18 V	0.6	0.85	—	W
G _P	f = 1025 — 1150 MHz	P _{IN} = 50 mW	V _{CE} = 18 V	10.8	12.3	—	dB

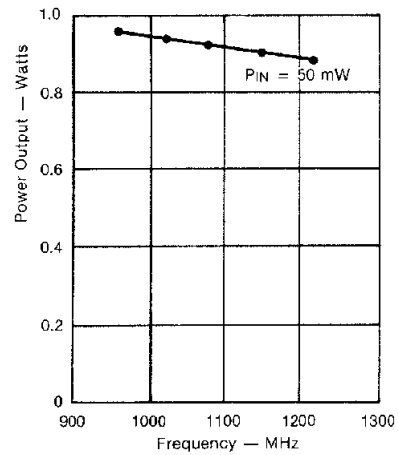
Note: Pulse Width = 10μSec I_C = 120mA
 Duty Cycle = 1%

TYPICAL PERFORMANCE

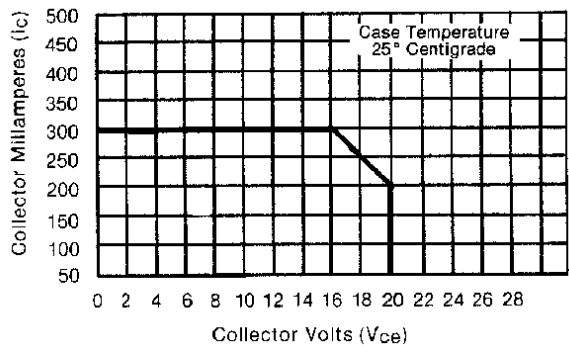
BROADBAND POWER AMPLIFIER



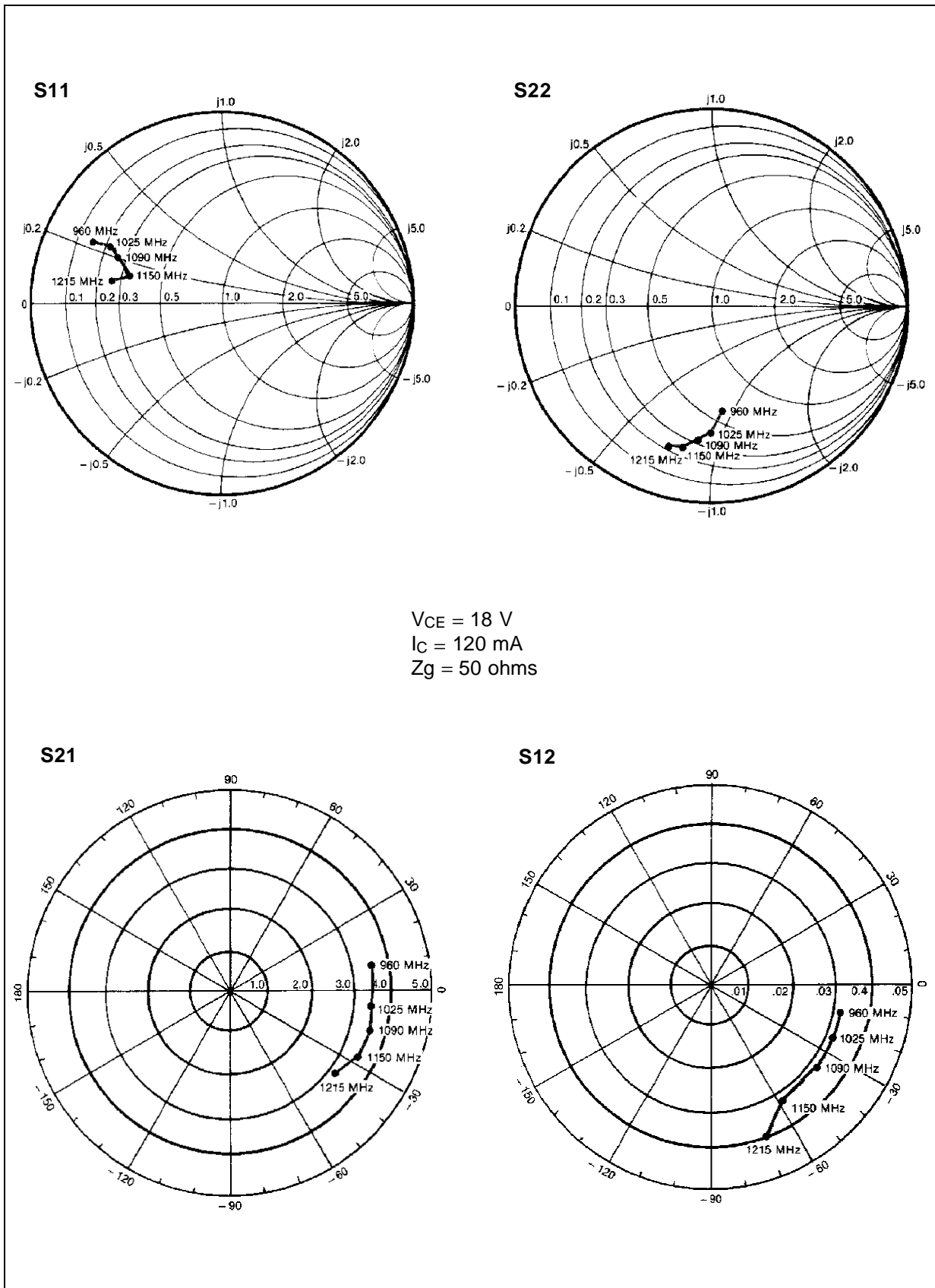
NARROWBAND POWER OUTPUT vs FREQUENCY



MAXIMUM OPERATING AREA for FORWARD BIAS OPERATION



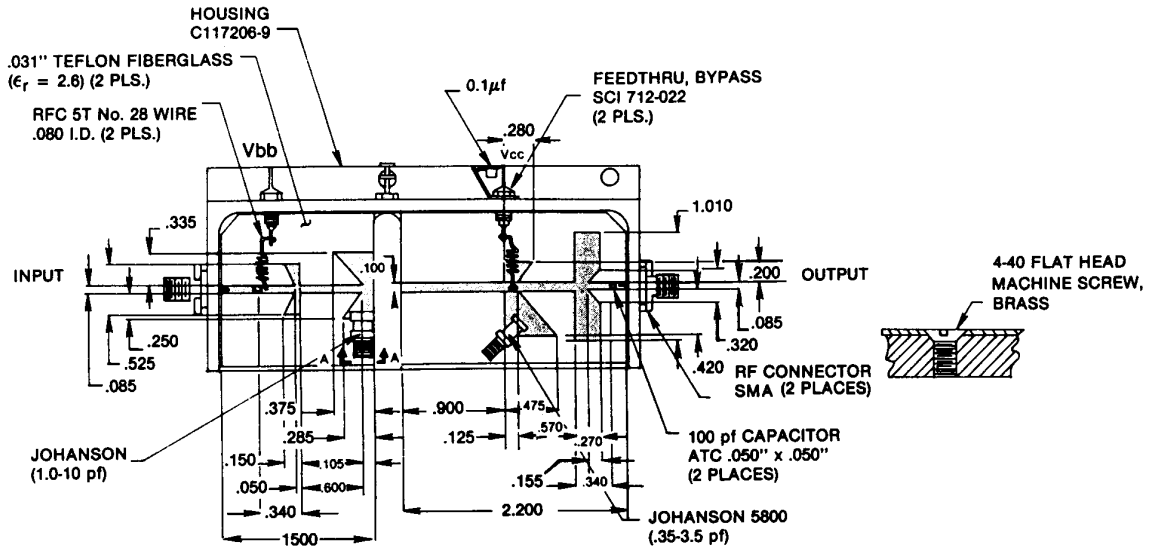
TYPICAL S-PARAMETERS



MSC1000M

TEST CIRCUIT

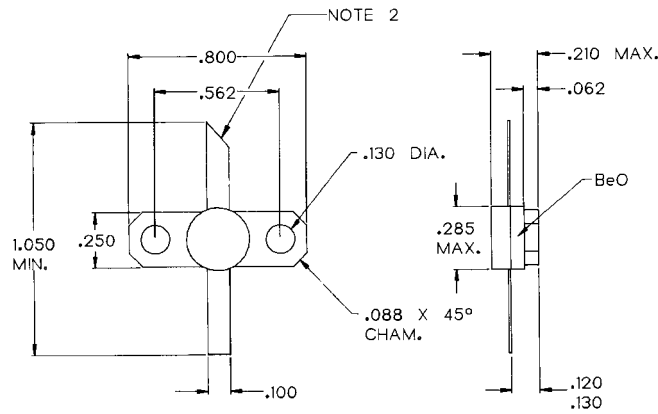
Ref.: Dwg No. C127297



All dimensions are in inches.

PACKAGE MECHANICAL DATA

Ref.: Dwg. No.: J135039B



- NOTES:
1. ALL TOLERANCE $\pm .010$ EXCEPT WHERE NOTED; DIMENSIONS IN INCHES.
 2. COLLECTOR LEAD SLANT CUT.

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